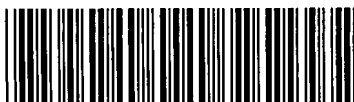


Search Notes

Application/Control No.

10/646,708

Examiner

Patrick J. Lee

Applicant(s)/Patent under
Reexamination

ECKER ET AL.

Art Unit

2878

SEARCHED

Class	Subclass	Date	Examiner
250	227.14, 227.16	12/12/2005	PL
385	10, 12	12/12/2005	PL
385	13, 37	12/12/2005	PL
Updated	search	5/30/2006	PL
Updated	search	10/30/2006	PL
Updated	search	5/15/2007	PL
Updated	search	5/18/2007	PL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted w/ S. Allen	8/4/2005	PL
Consulted w/ B. Healy AU 2883 CL 385	8/9/2005	PL
East (See attached)	8/9/2005	PL
East (see attached) - USPAT, US-PGPUB, EPO, JPO, DERWENT	12/12/2005	PL
East (see attached) - USPAT, US-PGPUB, EPO, JPO, DERWENT	5/30/2006	PL
East (see attached) - USPAT, US-PGPUB, EPO, JPO, DERWENT	10/30/2006	PL
East (see attached) - USPAT, US-PGPUB, EPO, JPO, DERWENT	5/15/2007	PL
East (see attached) - USPAT, US-PGPUB, EPO, JPO, DERWENT	5/18/2007	PL